

ABSTRACT OF THE DISCLOSURE

Method for the testing of electronic components

Method for the testing of an electronic component (1) in which a signal (S1) is sent to a cell (3) of the component, and the output signal (S2) of this component is studied so as to define whether the component is acceptable or not. If the component is acceptable then, according to the method, the test is performed again by sending a signal (S1') similar to the first signal but with a shorter duration (T2). A search is then made for an output signal (S2') to be compared with a compressed expected pattern. If this test, which is performed more rapidly, is valid, it can be envisaged, if necessary, to use this faster input signal on following components to be tested.

Figure 2a



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